U.S. DEPARTM PATENT AND	ENT C TRADI IRMA TEME	(SUBSTITUTE) OF COMMERCE EMARK OFFICE ATION DISCLOSURE ENT BY APPLICAN CFR 1.97(b)(1)		Attorney Docket No.: Applic. No. 2004P00018 Concurrently herewith Applicant HIEROLD, Christofer, et al. Filing Date Group Art Unit September 5, 2006 2855					
EXAMINER INITIALS	Ţ <u></u>	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE		
/PP/	Α	2002/0167374 A1	11/2002	Hunt, et al.					
	В	·							
	С								
	D					:			
	E								
	F				ļ				
	G								
					ļ				
	I		<u></u>		<u> L</u>	<u> </u>			
		FORE	GN PATE	NT DOCUMENT					
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO		
	J								
	K								
	L								
,	М				<u> </u>	<u> </u>			
	N		<u> </u>		<u> </u>				
C	ТНЕ	R DOCUMENTS (In	cluding Au	ithor, Title, Date, Pe	rtinent Pag	ges, etc.)			
EXAMINER	/Pur	nam Patel/		DATE CONSIDERED 08/26/2007					
	tation	if citation considered, if not in conformance a plicant.					9; Draw		

U.S. DEPARTM	ENT OF			Attorney Docket No.: 2004P00018		Applic. No. 10/591,879						
PATENT AND T		IARK OFFICE ON DISCLOSURE T BY APPLICANT		Applicant Christofer Hierold et al.								
		FR § 1.98(b))	Filing Date September 5, 2006		Group Art Unit NAC PP 2855							
A TRADEBALL		U.S. F	PATENT	DOCUMENTS								
EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILI DA					
· · · · · · · · · · · · · · · · · · ·	A			· · · · · · · · · · · · · · · · · · ·								
	В		.									
 .	D			 								
	E											
-	F											
	G			·								
	H											
	1			.].								
		FOREIC	ON PATE	NT DOCUMENT								
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRAI YES					
	J											
· ·	K					ļ	ļ	ļ				
	L						ļ	-				
OTH	TM IER D	CUMENTS (Inclu	l uding Aut	hor, Title, Date, Pe	ertinent P	ages, etc.	.)	<u> </u>				
/PP/	N	Tombler et al.: "Reversible electromechanical characteristics of carbon nanotubes under local- probe manipulation", Nature, June 15, 2000										
/PP/	0	Husain et al.: "Nanowire- based very- high- frequency electromechanical resonator", Applied Physics letters, August 11, 2003										
/PP/	Р	Toriyama Toshiyuki et al.: " Piezoresistance measurement on single crystal silicon nanowires", Journal of Applied Physics, January 1, 2003										
EXAMINER	/Punam Patel/ DATE CONSIDERED 08/26/2007											
MPEP 609; [Draw lie		if not in	ther or not citation conformance and opplicant.								